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INFORMA	TION	DISC	LOSU			Application Number	09/955,712		
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			(2	Group Art Unit	1773 2872		
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Sheet	1	C	of	2	I C I	Attorney Docket Number	37000-0015		
U.S. PATENT	DOCUM	MENTS							
Examiner Initials	Cite No.1	<u>U.S</u> Number	I	Document Kind Code (if known)	2	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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^{1.} Unique citation designation number. 2. See attached Kinds of U.S. Patent Documents. 3. Enter office that issued the document, by the two-letter code (WIPO Standard ST.3). 4. For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 6. Applicant is to place a check mark here if English language Translation is attached.

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Under the Paperwork Reduction Act of 1995 no persons are required to respond to a collection of information unless it contains a valid OMB control number. Substitute for form 1449A/PTO COMPLETE IF KNOWN INFORMATION DISCLOSURE Application Number 09/955,712 STATEMENT BY APPLICAN Filing Date September 19, 2001 First Named Inventor (use as many sheets as necessary) **SHALAEV** Group Art Unit 1773 *7*872 Examiner Name Lavarias Sheet 2 of Attorney Docket Number 37000-0015 U.S. PATENT DOCUMENTS Examiner Cite U.S. Patent Document Name of Patentee or Date of Pages, Columns, Lines, No.1 Initials Applicant of Cited Kind Code Publication Where Relevant Document of Cited Passages or Relevant Number (if known) Document Figures Appear 5,817,410 Tsujimura et al. 10/06/1998 5,858,799 Yee et al. 01/12/1999 6,017,630 Tanaka et al. 01/25/2000 6,033,774 Yitzchaik et al 03/07/2000 6,034,809 Anemogiannis 03/07/2000 5,991,588 Salamon et al 11/23/1999 6,094,413 Guerra 07/25/2000 6,115,348 Guerra 09/05/2000 6,122,091 Russell 09/19/2000 FOREIGN PATENT DOCUMENTS **Examiner Initials** Cite Foreign Patent Document Name of Patentee of Date of Pages, Columns, Lines No. Kind Applicant of Cited Publication Where Relevant Code 5 Number 4 Document of Cited Passages or Relevant Document Figures Appear T (if known) NANE Examiner Date Considered Signature Javanas

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					Application Number	09/955,712
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Filing Date	September 19, 2001			
					First Named Inventor	Vladimir M. SHALAEV
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		Examiner Name	Lavarias APRO			
Sheet	1	of		2	Attorney Docket Number	37000-0015 J 2002
OTHER P	RIOR	ART - N	ON P	PATENT LITERA	ATURE DOCUMENTS	9 00
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th	V	GRESILLON S., et al., "Experimental Observation of Localized Optical Excitations in Random RMetal-Dielectric Films," <i>Physical Review Letters</i> , Vol. 82, No. 22, pp 4520-4523 (May 31, 1999)	
Au	~	SARYCHEV, A.K., et al., "Anderson Localization of Surface Plasmons and Nonlinear Optics of Metal Dielectric Composites," <i>Physical Review B</i> , Vol. 60, No. 24, pp 16389 - 16408 (December 16 1999 II)	
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Ag	\	CHANG, R.K., et al., Editors "Optical Processes in Microcavities, World Scientific - Singapore- New Jersey-London-Hong Kong pp 1-75 (1996)	/
Au	(PRAESLER, M.A., "Near-Field Optics Theory, Instrumentation, and Applications, Wiley- Interscience Publication of John Wiley & Sons, Inc., New York, pp 1-65 (1996)	

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respond to a collection of information unless it contains a valid OMB control number. Under the Paperwork Reduction Act of 1995, no COMPLETE IF KNOWN Substitute for form 1449B/PTO Application Number 09/955,712 INFORMATION DISCLOSURE September 19, 2001 Filing Date STATEMENT BY APPLICANT Vladimir M. SHALAEV First Named Inventor (use as many sheets as necessary) 1515 2872 Group Art Unit **Examiner Name** avarias 2 2 Attorney Docket Number Sheet of 37000-0015 OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of Examiner Cite the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), Initials No. 1 publisher, city and/or country where published CRANE, R., et al., Editors, "Materials for Optical Limiting," Materials Research Society Symposium Proceedings, Vol. 374, Table of Contents (November 28, 1994) MOOD, P., et al., Editors, "Materials for Optical Limiting II," Materials Research Society Symposium Proceedings,, Vol. 479, Table of Contents (March 31, 1997) TURRO, N.J., "Modern Molecular Photochemistry, University Science Books, Columbia University, Sausalito, Californiam Chapter 11.1 - 1.10 (1991) SERPONE, N., "Photocatalysis - Fundamentals and Applications," J. Wiley & Sons, Wiley Interscience Publication, New York Chapterr 1 and 7 (1989) KOHEN, E., et al., "PhotoBiology," Academic Press, San Diego, New York, Boston, London, Sydney, Tokyo Toronto, 4-6 and 9 (1995) PETRANOVSKII, V., et al., "Plasmon Resonance of Copper Nanoparticles Withhin Zeolites: The Effect of Matrix Composition and Agglomeration Temperature," Proc of SPIE, Vol. 4467 (2001)Date Examiner Considered Signature

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				Application Number	09/955,712	
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				First Named Inventor	Vladimir M. SHALAEV	
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				Examiner Name	Lavarias	
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Cite No.	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
\checkmark	GORNIK, E., "Geometrical Shaping of Microlaser Emission Patterns," <i>Science</i> , Vol. 280, pp 1544-1545 (June 5, 1998)	
V	NÖCKEL, J.U., et al., "Chaotic Light: A Theory of Asymmetric Resonant Cavities," <i>Optical Processes in Microcavities</i> , edited by R.K. Chang and A.J. Campillo (World Scientific Publishers (1996),	
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STATEMENT BY APPLICANT	Filing Date	September 19, 2001
%	First Named Inventor	V.M. SHALAEV, et al.
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	Examiner Name	Lavarias
of 2	Attorney Docket Number	37000-0015

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